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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/808,499	03/25/2004	Hidekazu Miyairi	0756-7275	5721
31780 ERIC ROBINS	7590 02/19/200 ON		EXAMINER	
PMB 955			WEST, JEFFREY R	
21010 SOUTHBANK ST. POTOMAC FALLS, VA 20165			ART UNIT	PAPER NUMBER
			2857	
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			02/19/2009	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)		
10/808,499	MIYAIRI ET AL.		
Examiner	Art Unit		
Jeffrey R. West	2857		

	Jeffrey R. West	2857	
The MAILING DATE of this communication appe	ars on the cover sheet with the o	correspondence add	ress
THE REPLY FILED <u>23 January 2009</u> FAILS TO PLACE THIS A		-	
The reply was filed after a final rejection, but prior to or on application, applicant must timely file one of the following application in condition for allowance; (2) a Notice of Apperior Continued Examination (RCE) in compliance with 37 C periods:	the same day as filing a Notice of A eplies: (1) an amendment, affidavi al (with appeal fee) in compliance	Appeal. To avoid abar t, or other evidence, w with 37 CFR 41.31; or	hich places the (3) a Request
 a) The period for reply expires 5 months from the mailing date b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire la Examiner Note: If box 1 is checked, check either box (a) or (MONTHS OF THE FINAL REJECTION. See MPEP 706.07(f) 	dvisory Action, or (2) the date set forth tter than SIX MONTHS from the mailing b). ONLY CHECK BOX (b) WHEN THE	g date of the final rejection	n.
Extensions of time may be obtained under 37 CFR 1.136(a). The date thave been filed is the date for purposes of determining the period of extender 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b). NOTICE OF APPEAL	on which the petition under 37 CFR 1.1 ension and the corresponding amount of hortened statutory period for reply origi	of the fee. The appropria nally set in the final Offic	te extension fee e action; or (2) as
2. The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exter Notice of Appeal has been filed, any reply must be filed wi	sion thereof (37 CFR 41.37(e)), to	avoid dismissal of the	
3. ☑ The proposed amendment(s) filed after a final rejection, b (a) ☑ They raise new issues that would require further cor (b) ☐ They raise the issue of new matter (see NOTE below	sideration and/or search (see NO		cause
(c) They are not deemed to place the application in better appeal; and/or	•	ducing or simplifying th	ne issues for
(d) ☐ They present additional claims without canceling a c NOTE: <u>See Continuation Sheet</u> . (See 37 CFR 1.1)		ected claims.	
 The amendments are not in compliance with 37 CFR 1.12 Applicant's reply has overcome the following rejection(s): 		mpliant Amendment (I	PTOL-324).
6. Newly proposed or amended claim(s) would be all non-allowable claim(s).		timely filed amendmer	t canceling the
7. For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is proved the status of the claim(s) is (or will be) as follows:		l be entered and an ex	xplanation of
Claim(s) allowed: Claim(s) objected to: Claim(s) rejected: Claim(s) withdrawn from consideration:			
AFFIDAVIT OR OTHER EVIDENCE			
 The affidavit or other evidence filed after a final action, but because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e). 	sufficient reasons why the affidavi	t or other evidence is	necessary and
9. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to o showing a good and sufficient reasons why it is necessary	vercome <u>all</u> rejections under appea	al and/or appellant fails	to provide a
10. ☐ The affidavit or other evidence is entered. An explanation REQUEST FOR RECONSIDERATION/OTHER	n of the status of the claims after er	ntry is below or attache	ed.
11. The request for reconsideration has been considered but	does NOT place the application in	condition for allowand	ce because:
12. ☐ Note the attached Information <i>Disclosure Statement</i>(s). (13. ☐ Other:	PTO/SB/08) Paper No(s)		
	/Jeffrey R. West/ Primary Examiner, Art U	nit 2857	

Continuation Sheet (PTO-303)

Application No.

The proposed amendment to independent claims 1, 3, 26, and 28 changing "comparing a variance" to ---comparing a fluctuation--- and specifying that the reference value "is determined for a demanded performance of the semiconductor element" are considered to be new issues that would require additional search and/or consideration.

Applicant argues, "The Official Action sets forth an unreasonably narrow interpretation of the term 'variance' and, based on this interpretation, rejects the claims under § 112, first paragraph...The meaning of the term "variance" need not necessarily be limited to the statistical definitions provided by the Examiner. In addition to the specific meanings noted above, the Applicant respectfully submits that it is equally (if not more) well known that the term 'variance' means, more generally, 'the fact, quality, or state of being variable or variant' and is not limited to a specific statistical meaning as asserted in the Official Action. Also, the present specification uses a term that is similar to 'variation,' i.e. 'fluctuation' and its variants, to disclose the concept of the present invention."

The Examiner asserts that the claims as filed March 19, 2007, required "testing the crystallinity of the semiconductor film, of which the crystallinity is improved, using a fluctuation obtained from relations between the approximate line and the average values." This limitation was then rejected by a combination of Tsumura et al. in view of Ozawa et al. and further in view of Tanaka et al. and others with Ozawa teaching obtaining an approximate line from relations between the positions in the Y direction and the average values of the luminance corresponding to the positions in the Y direction, and testing the device surface using a fluctuation obtained from relations between the approximate line and the average values of the luminance (column 8, lines 3-20), specifically:

In each of the rows corresponding to X coordinate positions "151," "152," . . . of the unit blocks arranged in Y direction, that is, in each of the row with peak values positioned therein on the image and the rows adjacent thereto, the luminances of unit blocks are added. FIG. 4C represents added luminance values graphically with respect to each of the rows arranged in Y direction. In each of the rows of X coordinate positions "151," "152," "153," luminance values are added and then compared for each row. In the same figure, if a curved line connecting the added values is drawn, a peak position (a predicted peak position) of that curved line can be specified to be the position of the boundary line of the slider edge portion X0.

Alternatively, there may be adopted a method wherein, in each of the rows extending in Y direction, a mean luminance value in unit blocks pixels) is determined to draw the curved line shown in FIG. 4C, and a peak value of the curved line is specified to be the position of the edge portion X0.

In a subsequent response filed October 29, 2007, Applicant amended "testing the crystallinity of the semiconductor film, of which the crystallinity is improved, using a fluctuation obtained from relations between the approximate line and the average values" to recite --- comparing a variance obtained from relations between the approximate line and the average values with a reference value to evaluate the crystallinity of the semiconductor film having the crystallinity that has been improved--- and argued that "Independent claims 1, 3, 26 and 28 have been amended to recite comparing a variance obtained from relations between an approximate line and average values with a reference value to evaluate crystallinity of a semiconductor film having the crystallinity that has been improved".

As such, in addition to the fact that one having ordinary skill in the art would recognize the specific meaning of variance to be the mathematical variance, as opposed to variation and/or fluctuation that has a broader definition, the Examiner asserts that the record makes it clear that a "variance" and a "fluctuation" are different since the claim was amended to change "fluctuation" to "variance" in response to a rejection using Ozawa's teach of obtaining a fluctuation.

The Examiner also asserts that since the claimed variance is being changed back to the previously claimed fluctuation, which was rejected by the teachings of Ozawa, that such an amendment requires, at very least, additional reconsideration of Ozawa with respect to the limitations as currently amended.

/JRW/